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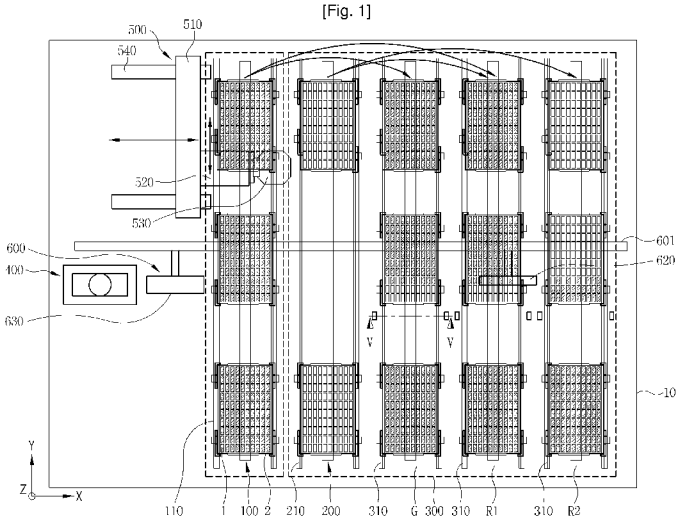
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(54) **Title:** APPARATUS FOR INSPECTING SEMICONDUCTOR DEVICE

[Fig. 1]



(57) **Abstract:** An apparatus for inspecting semiconductor device, relating to an apparatus for inspecting semiconductor device, and more particularly to an apparatus for inspecting semiconductor device for inspecting upper and lower external appearance of semiconductor device, the apparatus comprising: a transferring tool for transferring a plurality of semiconductor devices picked up by a plurality of pickers for picking up semiconductor device, the plurality of pickers being arranged in m columnsxn rows (m and n are a natural number not less than 2); and an image acquisition unit for acquiring image of lower external appearance of a plurality of semiconductor devices transferred by the transferring tool in order to inspect external state for semiconductor devices by analyzing image of lower external appearance of semiconductor devices, is disclosed.

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